

This is a repository copy of *Characterization of room temperature AlGaAs soft X-ray mesa photodiodes*.

White Rose Research Online URL for this paper: http://eprints.whiterose.ac.uk/89851/

Version: Accepted Version

Article:

Barnett, A.M., Lioliou, G. and Ng, J.S. (2014) Characterization of room temperature AlGaAs soft X-ray mesa photodiodes. Nuclear Instruments and Methods in Physics Research Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 774. 29 - 33. ISSN 0168-9002

https://doi.org/10.1016/j.nima.2014.11.039

Reuse

Unless indicated otherwise, fulltext items are protected by copyright with all rights reserved. The copyright exception in section 29 of the Copyright, Designs and Patents Act 1988 allows the making of a single copy solely for the purpose of non-commercial research or private study within the limits of fair dealing. The publisher or other rights-holder may allow further reproduction and re-use of this version - refer to the White Rose Research Online record for this item. Where records identify the publisher as the copyright holder, users can verify any specific terms of use on the publisher's website.

Takedown

If you consider content in White Rose Research Online to be in breach of UK law, please notify us by emailing eprints@whiterose.ac.uk including the URL of the record and the reason for the withdrawal request.



Table 1. Layer details of the AlGaAs wafer from which the diodes were fabricated.

Figure 1. Calculated quantum efficiency of the photodiodes used in this work (solid line). For comparison, the quantum efficiencies of the photodiodes used in refs. [9,17] are also shown (long dashes and short dashes, respectively).

Figure 2. Measured leakage currents of the devices as functions of applied reverse bias. Diode 1 -diamonds; Diode $2 - \times$ symbol; Diode 3 -stars; Diode 4 - + symbol; Diode 5 -long dash; Diode 6 -short dash; Diode 7 -squares; Diode 8 -triangles; Diode 9 -circles.

Figure 3. ⁵⁵Fe spectrum obtained with Diode 3 reverse biased at 5 V. The dashed lines are the fitted Mn K α and K β peaks.

Figure 4. Measured FWHM at 5.9 keV for Diodes 1 - 9 when reverse biased at 5 V (circles) and Diodes 1 - 6 when reverse biased at 10 V (squares). Also shown at the mean FWHM at each reverse bias (long dashes and short dashes, respectively).

Figure 5. Computed noise contributions for the diodes reverse biased at 5 V. Total FWHM – diamonds; Stray capacitances and dielectrics – short dashes; Known dielectrics – stars; Series white noise – triangles; Calculated charge trapping – + symbol; Parallel white noise – squares; Fano noise – circles; 1/f noise – × symbol.